IFFE SiPhotonics-**A Calibration Technique for Microring Modulator Thermal Controller**

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April 15th, 2024

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Thermal Controller

A Calibration Technique for Microring Modulator

Motivation





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Silicon photonics higher BW, lower power MRM better choice with respect to MZM Inherent WDM functionality to reduce area Sensitive to PVT variation How to reach max OMA

Background

Drop-port



Background



The ring's resonance is a strong function of temperature The goal is to observe OMA or a related parameter and change the temperature to arrive at maximum OMA How to observe OMA? How to stabilize the temperature? ш

~50 pm/ C 1312 1313 Wavelength (nm)





Ш Actuator:

Thermal Control Unit (TCU)

Drop-port (dedicated to each channel, suitable for WDM) Through-port (not compatible with WDM)

Heater resistor can be used to thermally lock the resonance wavelength

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To stabilize the temperature and maximize OMA we need sensor and actuator Sensors can either sense temperature (not sufficient) or laser power For laser power sensor, a photodiode can be located at either:

Through-Port vs Drop-Port Methods



Through-Port Method

Monitor the average power of the modulated laser OMA is a function of average power \Box Find the ratio of P_t/P_i or P_d/P_i that maximizes OMA Set the locking point accordingly by adjusting R1,2

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Prior works [4,5], used modeling and simulations for determination

Susceptibility to Process Variation

Through-Port Method



It results in zero OMA п

Subject to Process Variation

The result is a higher susceptibility to process variations \vec{t}

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Relying heavily on simulations and models to determine the locking point TCU fails to lock in 16% and 35% of the time in through-port and drop-port methods

Susceptibility to Process Variation

A target OMA of 0.5 mW, is expected to provide a yield of 61% and 36%, respectively

This Work

Utilizing a calibration method that locks to the max OMA, eliminates failures to lock It also increases expected yield to 83% for the target OMA

Proposed Design

Level 1 ----Level 0 -

Voltage Port Drop

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Wavelength

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Voltage Port Drop

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Wavelength

Voltage Port Drop

Voltage Port Drop

$$A_{DP_{0,1}}$$

$$4\left(\lambda_{n} \pm \frac{dl}{2\Delta\lambda}\right)^{2}$$

where

$$\lambda_n = \frac{\lambda - \lambda^*}{\Delta \lambda}$$

Voltage ort do

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Voltage ort do \square

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Voltage Port do \square

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$f(A_{DP_0}, A_{DP_1}, dl/\Delta\lambda)$

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Thermal Controller

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Measurement Results

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Goal is Our thread thread

Measurement Results

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Conclusion

- Implemented 8-channel WDM transmitter with on-chip TCU in monolithic GF45SPCLO technology
- TCU relies on average power of the modulated laser
- Verified locking to max OMA with a new calibration technique without any high
 - speed circuitry or relying on simulations
- OMA is expected to become significantly more stable against process variations
- Leading to an enhancement in yield from 36% to 83%

References

[1] C. Sun et al., "A 45 nm CMOS-SOI Monolithic Photonics Platform With Bit-Statistics-Based Resonant Microring Thermal Tuning," in IEEE Journal of Solid-State Circuits, vol. 51, no. 4, pp. 893-907, April 2016, doi: 10.1109/JSSC.2016.2519390 [2] H. Li et al., "A 25 Gb/s, 4.4 V-Swing, AC-Coupled Ring Modulator-Based WDM Transmitter with Wavelength Stabilization in 65 nm CMOS," in IEEE Journal of Solid-State Circuits, vol. 50, no. 12, pp. 3145-3159, Dec. 2015, doi: 10.1109/JSSC.2015.2470524 [3] S. Agarwal et al., "Wavelength Locking of a Si Ring Modulator Using an Integrated Drop-Port OMA Monitoring Circuit," in IEEE Journal of Solid-State Circuits, vol. 51, no. 10, pp. 2328-2344, Oct. 2016, doi: 10.1109/JSSC.2016.2592691. [4] H. Li et al., "12.1 A 3D-Integrated Microring-Based 112Gb/s PAM-4 Silicon-Photonic Transmitter with Integrated Nonlinear Equalization and Thermal Control," 2020 IEEE International Solid- State Circuits Conference - (ISSCC), San Francisco, CA, USA, 2020, p. [5] J. Sharma et al., "Silicon Photonic Microring-Based 4 \times 112 Gb/s WDM Transmitter With Photocurrent-Based Thermal Control in 28-nm CMOS," in IEEE Journal of Solid-State Circuits, vol. 57, no. 4, pp. 1187-1198, April 2022, doi: 10.1109/JSSC.2021.3134221

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